Infineon Technologies - CY8C5666AXQ-LP004 Datasheet

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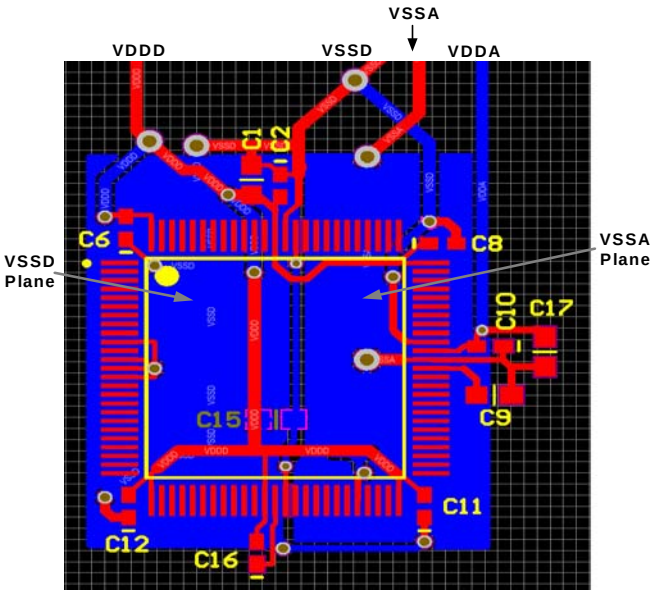
Applications of "Embedded - Microcontrollers"

Details	
Product Status	Obsolete
Core Processor	ARM® Cortex®-M3
Core Size	32-Bit Single-Core
Speed	67MHz
Connectivity	I²C, LINbus, SPI, UART/USART, USB
Peripherals	CapSense, DMA, LCD, POR, PWM, WDT
Number of I/O	62
Program Memory Size	64KB (64K x 8)
Program Memory Type	FLASH
EEPROM Size	2K x 8
RAM Size	16K x 8
Voltage - Supply (Vcc/Vdd)	1.71V ~ 5.5V
Data Converters	A/D 2x12b; D/A 4x8b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	100-LQFP
Supplier Device Package	100-TQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/cy8c5666axq-lp004

Figure 2-6. Example PCB Layout for 100-pin TQFP Part for Optimal Analog Performance



3. Pin Descriptions

IDAC0, IDAC1, IDAC2, IDAC3

Low resistance output pin for high current DACs (IDAC).

Opamp0out, Opamp1out, Opamp2out, Opamp3out

High current output of uncommitted opamp[7].

Extref0, Extref1

External reference input to the analog system.

SAR0 EXTREF, SAR1 EXTREF

External references for SAR ADCs

Opamp0–, Opamp1–, Opamp2–, Opamp3–

Inverting input to uncommitted opamp.

Opamp0+, Opamp1+, Opamp2+, Opamp3+

Noninverting input to uncommitted opamp.

GPIO

General purpose I/O pin provides interfaces to the CPU, digital peripherals, analog peripherals, interrupts, LCD segment drive, and CapSense[7].

I2C0: SCL, I2C1: SCL

I^2C SCL line providing wake from sleep on an address match. Any I/O pin can be used for I^2C SCL if wake from sleep is not required.

I2C0: SDA, I2C1: SDA

I^2C SDA line providing wake from sleep on an address match. Any I/O pin can be used for I^2C SDA if wake from sleep is not required.

Ind

Inductor connection to boost pump.

kHz XTAL: Xo, kHz XTAL: Xi

32.768-kHz crystal oscillator pin.

MHz XTAL: Xo, MHz XTAL: Xi

4 to 25 MHz crystal oscillator pin.

nTRST

Optional JTAG Test Reset programming and debug port connection to reset the JTAG connection.

SIO. Special I/O provides interfaces to the CPU, digital peripherals and interrupts with a programmable high threshold voltage, analog comparator, high sink current, and high impedance state when the device is unpowered.

SWDCK

Serial Wire Debug Clock programming and debug port connection.

SWDIO

Serial Wire Debug Input and Output programming and debug port connection.

TCK

JTAG Test Clock programming and debug port connection.

TDI

JTAG Test Data In programming and debug port connection.

TDO

JTAG Test Data Out programming and debug port connection.

TMS

JTAG Test Mode Select programming and debug port connection.

TRACECLK

Cortex-M3 TRACEPORT connection, clocks TRACEDATA pins.

TRACEDATA[3:0].

Cortex-M3 TRACEPORT connections, output data.

SWV.

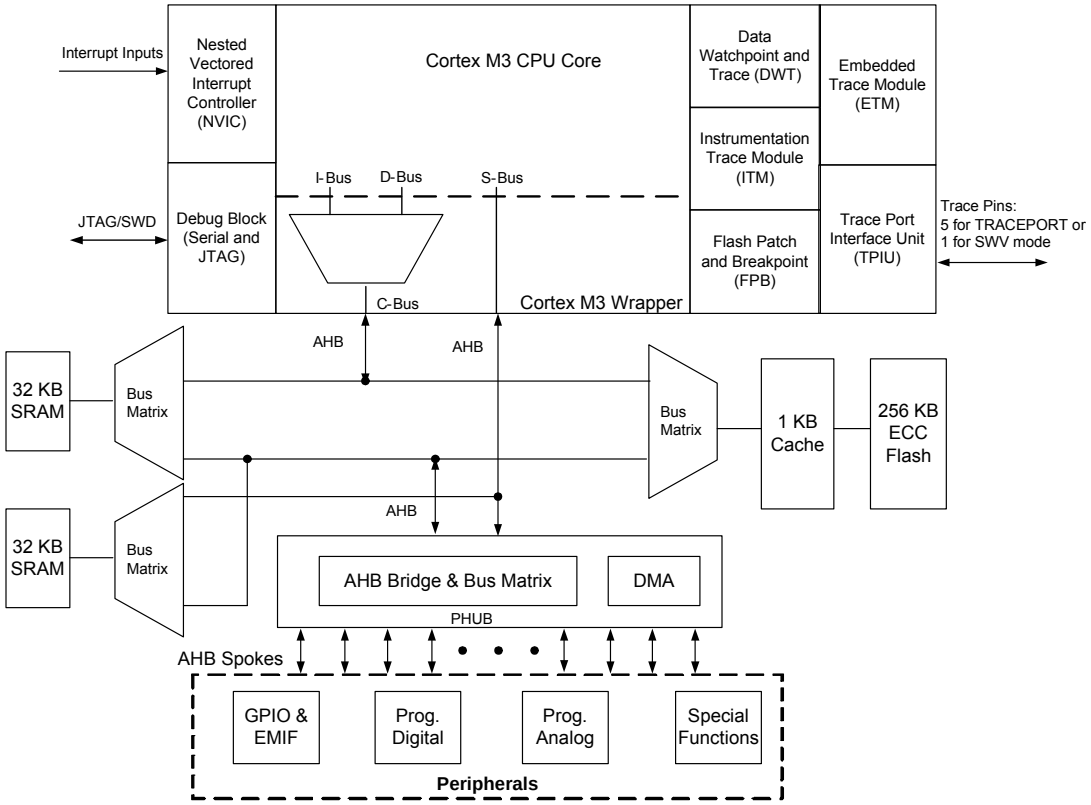
Single Wire Viewer output.

USBIO, D+

Provides D+ connection directly to a USB 2.0 bus. May be used as a digital I/O pin; it is powered from VDDD instead of from a VDDIO. Pins are Do Not Use (DNU) on devices without USB.

Note
7. GPIOs with opamp outputs are not recommended for use with CapSense.

Figure 4-1. ARM Cortex-M3 Block Diagram



The Cortex-M3 CPU subsystem includes these features:

- ARM Cortex-M3 CPU
- Programmable Nested Vectored Interrupt Controller (NVIC), tightly integrated with the CPU core
- Full featured debug and trace modules, tightly integrated with the CPU core
- Up to 256 KB of flash memory, 2 KB of EEPROM, and 64 KB of SRAM
- Cache controller
- Peripheral HUB (PHUB)
- DMA controller
- External Memory Interface (EMIF)

4.1.1 Cortex-M3 Features

The Cortex-M3 CPU features include:

- 4 GB address space. Predefined address regions for code, data, and peripherals. Multiple buses for efficient and simultaneous accesses of instructions, data, and peripherals.
- The Thumb®-2 instruction set, which offers ARM-level performance at Thumb-level code density. This includes 16-bit and 32-bit instructions. Advanced instructions include:
  - Bit-field control
  - Hardware multiply and divide
  - Saturation
  - If-Then
  - Wait for events and interrupts
  - Exclusive access and barrier
  - Special register access

  The Cortex-M3 does not support ARM instructions.
- Bit-band support for the SRAM region. Atomic bit-level write and read operations for SRAM addresses.
- Unaligned data storage and access. Contiguous storage of data of different byte lengths.
- Operation at two privilege levels (privileged and user) and in two modes (thread and handler). Some instructions can only be executed at the privileged level. There are also two stack pointers: Main (MSP) and Process (PSP). These features support a multitasking operating system running one or more user-level processes.
- Extensive interrupt and system exception support.

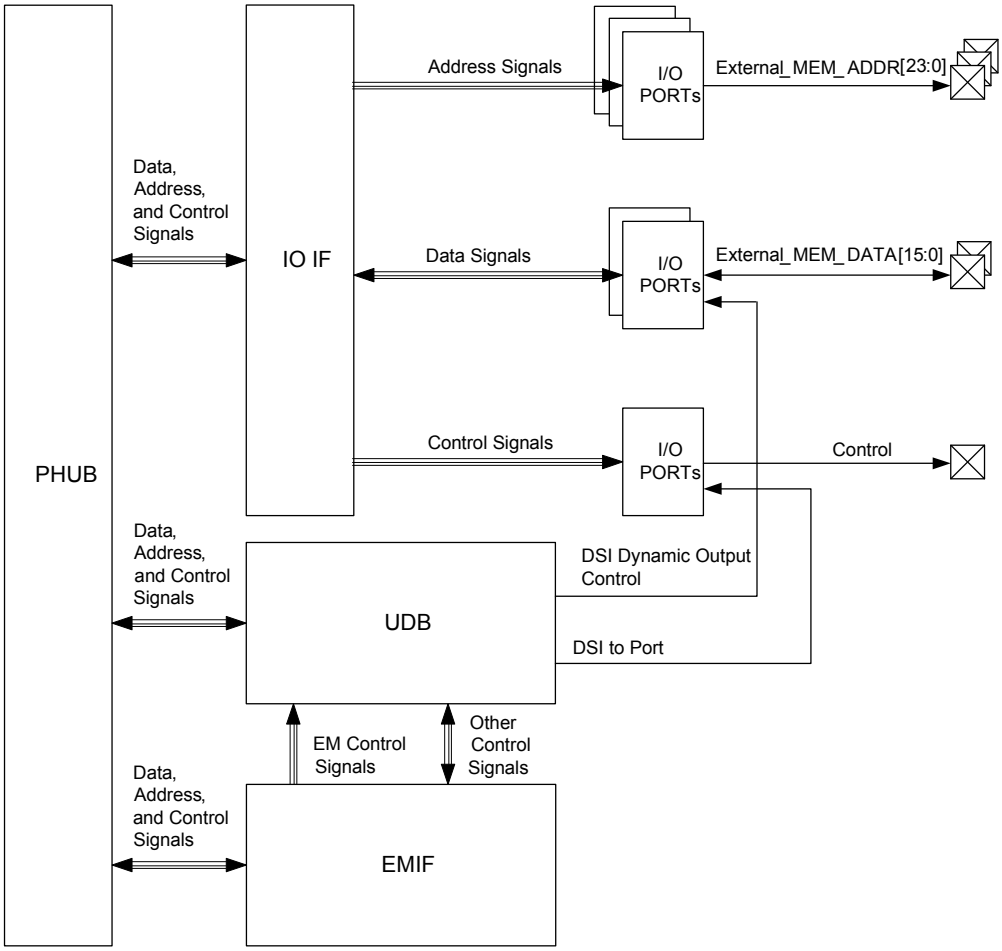
5.6 External Memory Interface

CY8C56LP provides an External Memory Interface (EMIF) for connecting to external memory devices. The connection allows read and write accesses to external memories. The EMIF operates in conjunction with UDBs, I/O ports, and other hardware to generate external memory address and control signals. At 33 MHz, each memory access cycle takes four bus clock cycles. Figure 5-1 is the EMIF block diagram. The EMIF supports synchronous and asynchronous memories. The CY8C56LP only supports one type of external memory device at a time.

External memory is located in the Cortex-M3 external RAM space; it can use up to 24 address bits. See Table 5-4 on page 22Memory Map on page 22. The memory can be 8 or 16 bits wide.

Cortex-M3 instructions can be fetched from external memory if it is 16-bit. Other limitations apply; for details, see application note AN89610, PSoC® 4 and PSoC 5LP ARM Cortex Code Optimization. There is no provision for code security in external memory. If code must be kept secure, then it should be placed in internal flash. See Flash Security on page 19 and Device Security on page 64.

Figure 5-1. EMIF Block Diagram



6.2.1 Power Modes

PSoC 5LP devices have four different power modes, as shown in Table 6-2 and Table 6-3. The power modes allow a design to easily provide required functionality and processing power while simultaneously minimizing power consumption and maximizing battery life in low power and portable devices.

PSoC 5LP power modes, in order of decreasing power consumption are:

- Active
- Alternate Active
- Sleep
- Hibernate

Active is the main processing mode. Its functionality is configurable. Each power controllable subsystem is enabled or disabled by using separate power configuration template registers. In alternate active mode, fewer subsystems are enabled, reducing power. In sleep mode most resources are disabled regardless of the template settings. Sleep mode is optimized to provide timed sleep intervals and Real Time Clock functionality. The lowest power mode is hibernate, which retains register and SRAM state, but no clocks, and allows wakeup only from I/O pins. Figure 6-5 illustrates the allowable transitions between power modes. Sleep and hibernate modes should not be entered until all VDDIO supplies are at valid voltage levels.

Table 6-2. Power Modes

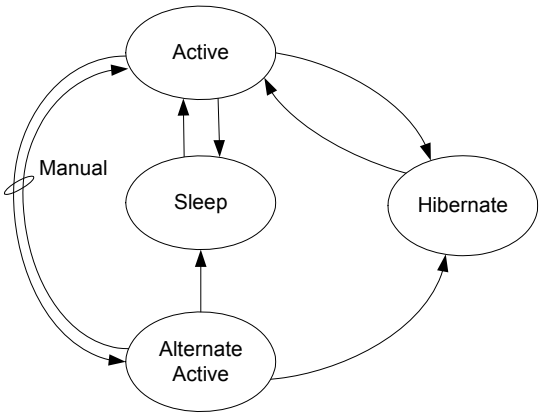
Power Modes	Description	Entry Condition	Wakeup Source	Active Clocks	Regulator
Active	Primary mode of operation, all peripherals available (programmable)	Wakeup, reset, manual register entry	Any interrupt	Any (programmable)	All regulators available. Digital and analog regulators can be disabled if external regulation used.
Alternate Active	Similar to Active mode, and is typically configured to have fewer peripherals active to reduce power. One possible configuration is to use the UDBs for processing, with the CPU turned off	Manual register entry	Any interrupt	Any (programmable)	All regulators available. Digital and analog regulators can be disabled if external regulation used.
Sleep	All subsystems automatically disabled	Manual register entry	Comparator, PICU, I^2C, RTC, CTW, LVD	ILO/kHzECO	Both digital and analog regulators buzzed. Digital and analog regulators can be disabled if external regulation used.
Hibernate	All subsystems automatically disabled Lowest power consuming mode with all peripherals and internal regulators disabled, except hibernate regulator is enabled Configuration and memory contents retained	Manual register entry	PICU		Only hibernate regulator active.

Table 6-3. Power Modes Wakeup Time and Power Consumption

Sleep Modes	Wakeup Time	Current (Typ)	Code Execution	Digital Resources	Analog Resources	Clock Sources Available	Wakeup Sources	Reset Sources
Active	–	3.1 mA[8]	Yes	All	All	All	–	All
Alternate Active	–	–	User defined	All	All	All	–	All
Sleep	<25 µs	2 µA	No	I^2C	Comparator	ILO/kHzECO	Comparator, PICU, I^2C, RTC, CTW, LVD	XRES, LVD, WDR
Hibernate	<200 µs	300 nA	No	None	None	None	PICU	XRES

Note
8. Bus clock off. Execute from CPU instruction buffer at 6 MHz. See Table 11-2 on page 67.

Figure 6-5. Power Mode Transitions



6.2.1.1 Active Mode

Active mode is the primary operating mode of the device. When in active mode, the active configuration template bits control which available resources are enabled or disabled. When a resource is disabled, the digital clocks are gated, analog bias currents are disabled, and leakage currents are reduced as appropriate. User firmware can dynamically control subsystem power by setting and clearing bits in the active configuration template. The CPU can disable itself, in which case the CPU is automatically reenabled at the next wakeup event.

When a wakeup event occurs, the global mode is always returned to active, and the CPU is automatically enabled, regardless of its template settings. Active mode is the default global power mode upon boot.

6.2.1.2 Alternate Active Mode

Alternate Active mode is very similar to Active mode. In alternate active mode, fewer subsystems are enabled, to reduce power consumption. One possible configuration is to turn off the CPU and flash, and run peripherals at full speed.

6.2.1.3 Sleep Mode

Sleep mode reduces power consumption when a resume time of 15 µs is acceptable. The wake time is used to ensure that the regulator outputs are stable enough to directly enter active mode.

6.2.1.4 Hibernate Mode

In hibernate mode nearly all of the internal functions are disabled. Internal voltages are reduced to the minimal level to keep vital systems alive. Configuration state is preserved in hibernate mode and SRAM memory is retained. GPIOs configured as digital outputs maintain their previous values and external GPIO pin interrupt settings are preserved. The device can only return from hibernate mode in response to an external I/O interrupt. The resume time from hibernate mode is less than 100 µs.

To achieve an extremely low current, the hibernate regulator has limited capacity. This limits the frequency of any signal present on the input pins; no GPIO should toggle at a rate greater than 10 kHz while in hibernate mode. If pins must be toggled at a high rate while in a low power mode, use sleep mode instead.

6.2.1.5 Wakeup Events

Wakeup events are configurable and can come from an interrupt or device reset. A wakeup event restores the system to active mode. Firmware enabled interrupt sources include internally generated interrupts, power supervisor, central timewheel, and I/O interrupts. Internal interrupt sources can come from a variety of peripherals, such as analog comparators and UDBs. The central timewheel provides periodic interrupts to allow the system to wake up, poll peripherals, or perform real-time functions. Reset event sources include the external reset pin (XRES), WDT, and Precision Reset (PRES).

6.2.2 Boost Converter

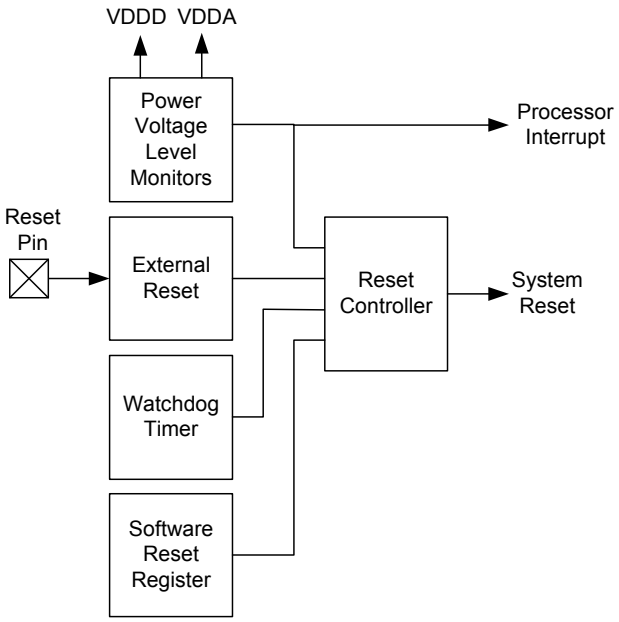
Applications that use a supply voltage of less than 1.71 V, such as solar panels or single cell battery supplies, may use the on-chip boost converter to generate a minimum of 1.8 V supply voltage. The boost converter may also be used in any system that requires a higher operating voltage than the supply provides such as driving 5.0 V LCD glass in a 3.3 V system. With the addition of an inductor, Schottky diode, and capacitors, it produces a selectable output voltage sourcing enough current to operate the PSoC and other on-board components.

The boost converter accepts an input voltage V_{BAT} from 0.5 V to 3.6 V, and can start up with V_{BAT} as low as 0.5 V. The converter provides a user configurable output voltage of 1.8 to 5.0 V (V_{OUT}) in 100 mV increments. V_{BAT} is typically less than V_{OUT}; if V_{BAT} is greater than or equal to V_{OUT}, then V_{OUT} will be slightly less than V_{BAT} due to resistive losses in the boost converter. The block can deliver up to 50 mA (I_{BOOST}) depending on configuration to both the PSoC device and external components. The sum of all current sinks in the design including the PSoC device, PSoC I/O pin loads, and external component loads must be less than the I_{BOOST} specified maximum current.

Four pins are associated with the boost converter: VBAT, VSSB, VBOOST, and IND. The boosted output voltage is sensed at the VBOOST pin and must be connected directly to the chip's supply inputs; VDDA, VDDD, and VDDIO if used to power the PSoC device.

The boost converter requires four components in addition to those required in a non-boost design, as shown in Figure 6-6 on page 29. A 22 µF capacitor (C_{BAT}) is required close to the VBAT pin to provide local bulk storage of the battery voltage and provide regulator stability. A diode between the battery and VBAT pin should not be used for reverse polarity protection because the diodes forward voltage drop reduces the V_{BAT} voltage. Between the VBAT and IND pins, an inductor of 4.7 µH, 10 µH, or 22 µH is required. The inductor value can be optimized to increase the boost converter efficiency based on input voltage, output voltage, temperature, and current. Inductor size is determined by following the design guidance in this chapter and electrical specifications. The Inductor must be placed within 1 cm of the VBAT and IND pins and have a minimum saturation current of 750 mA. Between the IND and VBOOST pins a Schottky diode must be placed within 1 cm of the pins. The Schottky diode shall have a forward current rating of at least 1.0 A and a reverse voltage of at least 20 V. A 22 µF bulk capacitor (C_{BOOST}) must be connected close to VBOOST to provide regulator output stability. It is important to sum the total capacitance connected to the VBOOST pin and ensure the maximum C_{BOOST} specification is not exceeded. All capacitors must be rated for a minimum of 10 V to minimize capacitive losses due to voltage de-rating.

Figure 6-8. Resets



The term **system reset** indicates that the processor as well as analog and digital peripherals and registers are reset.

A reset status register shows some of the resets or power voltage monitoring interrupts. The program may examine this register to detect and report certain exception conditions. This register is cleared after a power-on reset. For details see the Technical Reference Manual.

6.3.1 Reset Sources

6.3.1.1 Power Voltage Level Monitors

- IPOR - Initial Power-on-Reset

  At initial power on, IPOR monitors the power voltages V_{DDD}, V_{DDA}, V_{CCD} and V_{CCA}. The trip level is not precise. It is set to approximately 1 volt (0.75 V to 1.45 V). This is below the lowest specified operating voltage but high enough for the internal circuits to be reset and to hold their reset state. The monitor generates a reset pulse that is at least 150 ns wide. It may be much wider if one or more of the voltages ramps up slowly.

  After boot, the IPOR circuit is disabled and voltage supervision is handed off to the precise low-voltage reset (PRES) circuit.

- PRES - Precise Low-Voltage Reset

  This circuit monitors the outputs of the analog and digital internal regulators after power up. The regulator outputs are compared to a precise reference voltage. The response to a PRES trip is identical to an IPOR reset.

  In normal operating mode, the program cannot disable the digital PRES circuit. The analog regulator can be disabled, which also disables the analog portion of the PRES. The PRES circuit is disabled automatically during sleep and hibernate modes, with one exception: During sleep mode the regulators are periodically activated (buzzed) to provide supervisory services and to reduce wakeup time. At these times the PRES circuit is also buzzed to allow periodic voltage monitoring.

- ALVI, DLVI, AHVI - Analog/Digital Low Voltage Interrupt, Analog High Voltage Interrupt

  Interrupt circuits are available to detect when VDDA and VDDD go outside a voltage range. For AHVI, VDDA is compared to a fixed trip level. For ALVI and DLVI, VDDA and VDDD are compared to trip levels that are programmable, as listed in Table 6-5. ALVI and DLVI can also be configured to generate a device reset instead of an interrupt.

Table 6-5. Analog/Digital Low Voltage Interrupt, Analog High Voltage Interrupt

Interrupt	Supply	Normal Voltage Range	Available Trip Settings
DLVI	VDDD	1.71 V–5.5 V	1.70 V–5.45 V in 250-mV increments
ALVI	VDDA	1.71 V–5.5 V	1.70 V–5.45 V in 250-mV increments
AHVI	VDDA	1.71 V–5.5 V	5.75 V

  The monitors are disabled until after IPOR. During sleep mode these circuits are periodically activated (buzzed). If an interrupt occurs during buzzing then the system first enters its wakeup sequence. The interrupt is then recognized and may be serviced.

  The buzz frequency is adjustable, and should be set to be less than the minimum time that any voltage is expected to be out of range. For details on how to adjust the buzz frequency, see the TRM.

6.3.1.2 Other Reset Sources

- XRES - External Reset

  PSoC 5LP has a dedicated XRES pin, which holds the part in reset while held active (low). The response to an XRES is the same as to an IPOR reset.

  The external reset is active low. It includes an internal pull up resistor. XRES is active during sleep and hibernate modes.

  After XRES has been deasserted, at least 10 µs must elapse before it can be reasserted.

- SRES - Software Reset

  A reset can be commanded under program control by setting a bit in the software reset register. This is done either directly by the program or indirectly by DMA access. The response to a SRES is the same as after an IPOR reset.

  Another register bit exists to disable this function.

- WRES - Watchdog Timer Reset

  The watchdog reset detects when the software program is no longer being executed correctly. To indicate to the watchdog timer that it is running correctly, the program must periodically reset the timer. If the timer is not reset before a user-specified amount of time, then a reset is generated.

Figure 6-9. GPIO Block Diagram

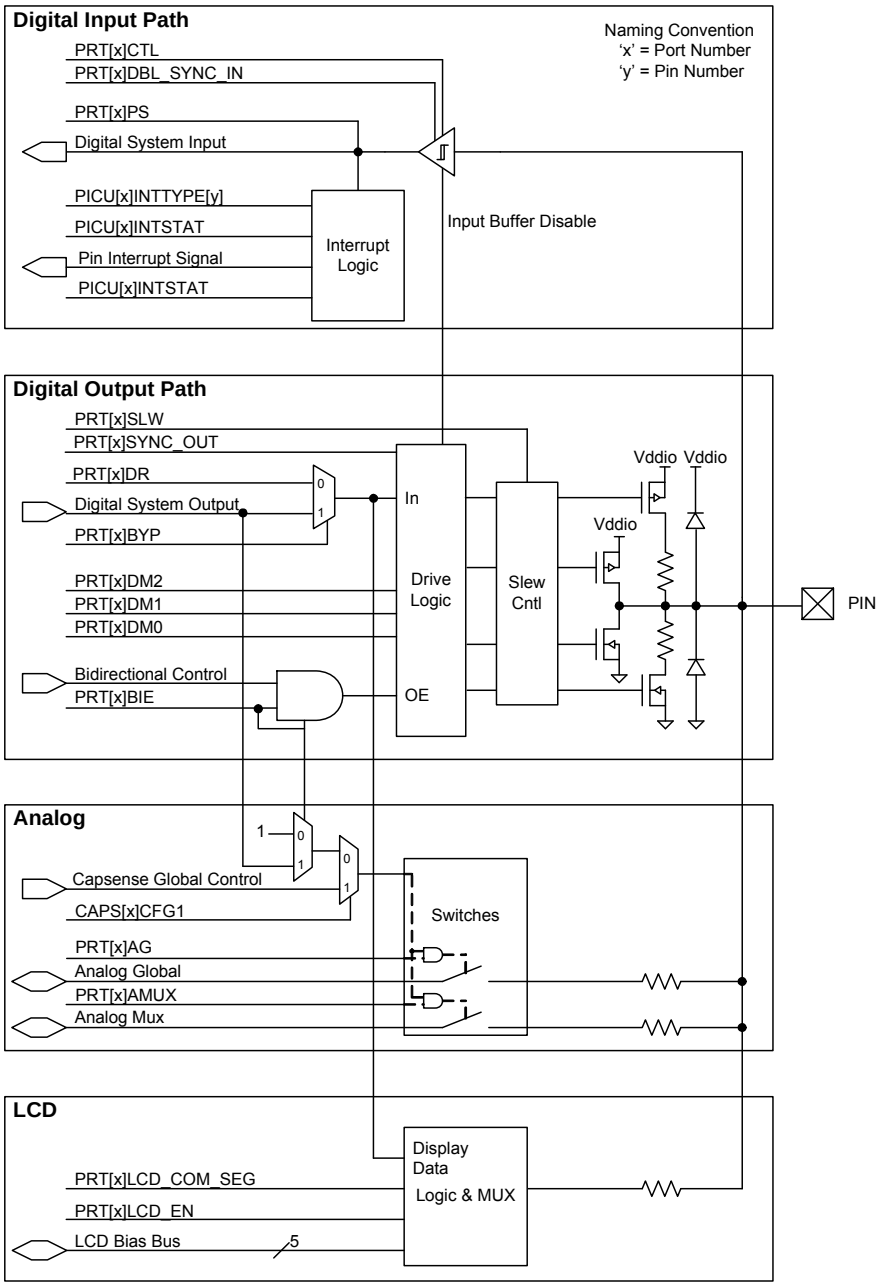
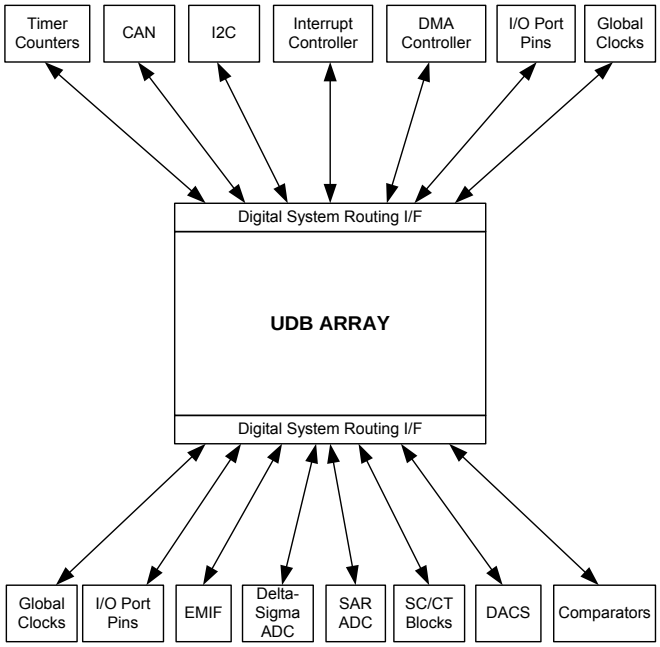
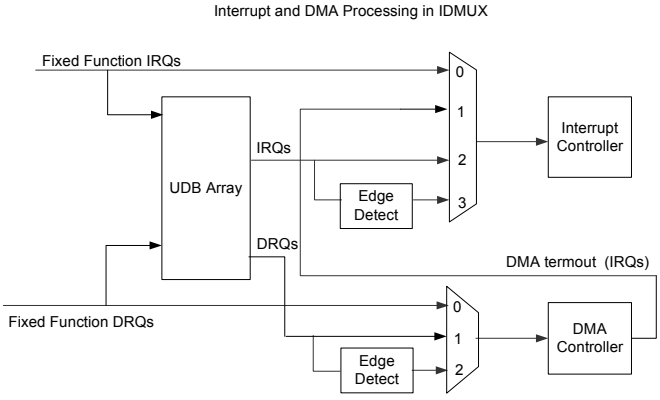


Figure 7-9. Digital System Interconnect



Interrupt and DMA routing is very flexible in the CY8C56LP programmable architecture. In addition to the numerous fixed function peripherals that can generate interrupt requests, any data signal in the UDB array routing can also be used to generate a request. A single peripheral may generate multiple independent interrupt requests simplifying system and firmware design. Figure 7-10 shows the structure of the IDMUX (Interrupt/DMA Multiplexer).

Figure 7-10. Interrupt and DMA Processing in the IDMUX



7.4.1 I/O Port Routing

There are a total of 20 DSI routes to a typical 8-bit I/O port, 16 for data and four for drive strength control.

When an I/O pin is connected to the routing, there are two primary connections available, an input and an output. In conjunction with drive strength control, this can implement a bidirectional I/O pin. A data output signal has the option to be single synchronized (pipelined) and a data input signal has the option to be double synchronized. The synchronization clock is the system clock (see Figure 6-1). Normally all inputs from pins are synchronized as this is required if the CPU interacts with the signal or any signal derived from it. Asynchronous inputs have rare uses. An example of this is a feed through of combinational PLD logic from input pins to output pins.

Figure 7-11. I/O Pin Synchronization Routing

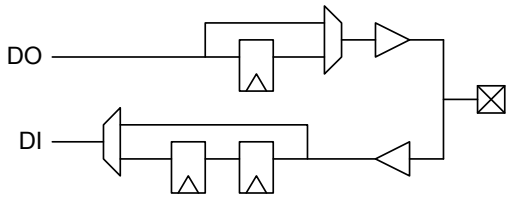
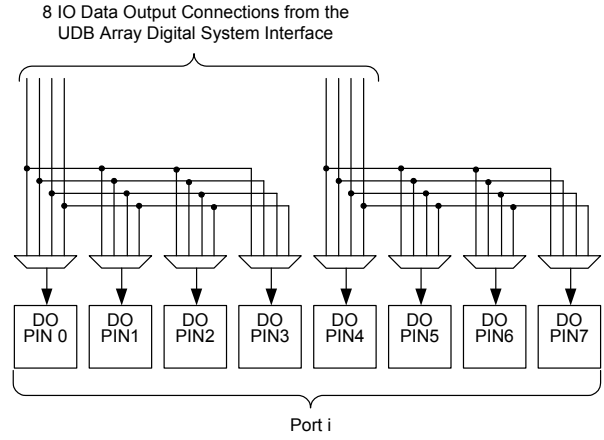
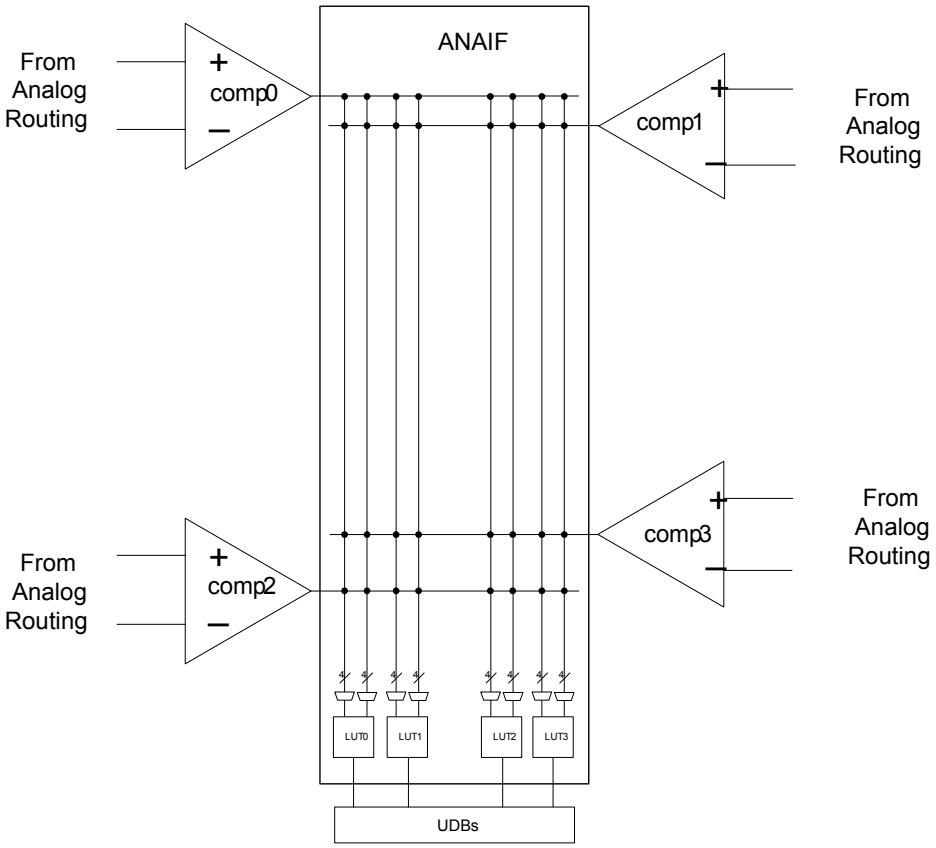


Figure 7-12. I/O Pin Output Connectivity



There are four more DSI connections to a given I/O port to implement dynamic output enable control of pins. This connectivity gives a range of options, from fully ganged 8-bits controlled by one signal, to up to four individually controlled pins. The output enable signal is useful for creating tri-state bidirectional pins and buses.

Figure 8-6. Analog Comparator



8.4.2 LUT

The CY8C56LP family of devices contains four LUTs. The LUT is a two input, one output lookup table that is driven by any one or two of the comparators in the chip. The output of any LUT is routed to the digital system interface of the UDB array. From the digital system interface of the UDB array, these signals can be connected to UDBs, DMA controller, I/O, or the interrupt controller.

The LUT control word written to a register sets the logic function on the output. The available LUT functions and the associated control word is shown in Table 8-2.

Table 8-2. LUT Function vs. Program Word and Inputs

Control Word	Output (A and B are LUT inputs)
0000b	**FALSE** (‘0’)
0001b	**A** AND **B**
0010b	**A** AND (NOT **B**)
0011b	A
0100b	(NOT **A**) AND **B**
0101b	B
0110b	**A** XOR **B**
0111b	**A** OR **B**
1000b	**A** NOR **B**
1001b	**A** XNOR **B**
1010b	NOT **B**
1011b	**A** OR (NOT **B**)
1100b	NOT **A**
1101b	(NOT **A**) OR **B**
1110b	**A** NAND **B**
1111b	**TRUE** (‘1’)

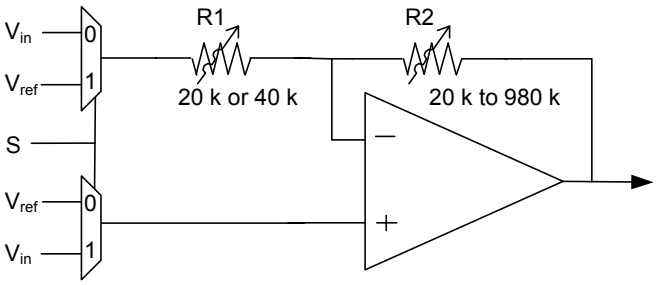
8.6.3 PGA

The PGA amplifies an external or internal signal. The PGA can be configured to operate in inverting mode or noninverting mode. The PGA function may be configured for both positive and negative gains as high as 50 and 49 respectively. The gain is adjusted by changing the values of R1 and R2 as illustrated in Figure 8-9. The schematic in Figure 8-9 shows the configuration and possible resistor settings for the PGA. The gain is switched from inverting and non inverting by changing the shared select value of the both the input muxes. The bandwidth for each gain case is listed in Table 8-3.

Table 8-3. Bandwidth

Gain	Bandwidth
1	6.0 MHz
24	340 kHz
48	220 kHz
50	215 kHz

Figure 8-9. PGA Resistor Settings



The PGA is used in applications where the input signal may not be large enough to achieve the desired resolution in the ADC, or dynamic range of another SC/CT block such as a mixer. The gain is adjustable at runtime, including changing the gain of the PGA prior to each ADC sample.

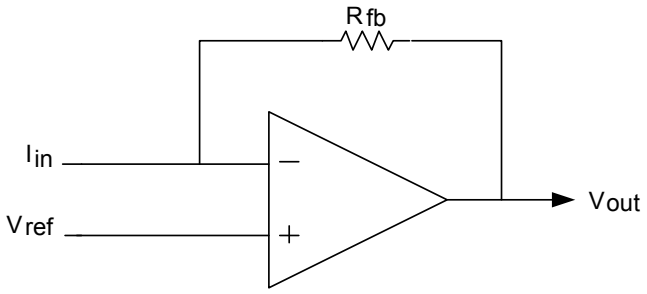
8.6.4 TIA

The Transimpedance Amplifier (TIA) converts an internal or external current to an output voltage. The TIA uses an internal feedback resistor in a continuous time configuration to convert input current to output voltage. For an input current I_{in}, the output voltage is V_{REF} - I_{in} x R_{fb}, where V_{REF} is the value placed on the non inverting input. The feedback resistor Rfb is programmable between 20 KΩ and 1 MΩ through a configuration register. Table 8-4 shows the possible values of Rfb and associated configuration settings.

Table 8-4. Feedback Resistor Settings

Configuration Word	Nominal R_{fb} (KΩ)
000b	20
001b	30
010b	40
011b	60
100b	120
101b	250
110b	500
111b	1000

Figure 8-10. Continuous Time TIA Schematic



The TIA configuration is used for applications where an external sensor's output is current as a function of some type of stimulus such as temperature, light, magnetic flux etc. In a common application, the voltage DAC output can be connected to the V_{REF} TIA input to allow calibration of the external sensor bias current by adjusting the voltage DAC output voltage.

8.7 LCD Direct Drive

The PSoC Liquid Crystal Display (LCD) driver system is a highly configurable peripheral designed to allow PSoC to directly drive a broad range of LCD glass. All voltages are generated on chip, eliminating the need for external components. With a high multiplex ratio of up to 1/16, the CY8C56LP family LCD driver system can drive a maximum of 736 segments. The PSoC LCD driver module was also designed with the conservative power budget of portable devices in mind, enabling different LCD drive modes and power down modes to conserve power.

PSoC Creator provides an LCD segment drive component. The component wizard provides easy and flexible configuration of LCD resources. You can specify pins for segments and commons along with other options. The software configures the device to meet the required specifications. This is possible because of the programmability inherent to PSoC devices.

Key features of the PSoC LCD segment system are:

- LCD panel direct driving
- Type A (standard) and Type B (low power) waveform support
- Wide operating voltage range support (2 V to 5 V) for LCD panels
- Static, 1/2, 1/3, 1/4, 1/5 bias voltage levels
- Internal bias voltage generation through internal resistor ladder
- Up to 62 total common and segment outputs
- Up to 1/16 multiplex for a maximum of 16 backplane/common outputs
- Up to 62 front plane/segment outputs for direct drive
- Drives up to 736 total segments (16 backplane x 46 front plane)
- Up to 64 levels of software controlled contrast

9.2 SWD Interface

The SWD interface is the preferred alternative to the JTAG interface. It requires only two pins instead of the four or five needed by JTAG. SWD provides all of the programming and debugging features of JTAG at the same speed. SWD does not provide access to scan chains or device chaining. The SWD clock frequency can be up to 1/3 of the CPU clock frequency.

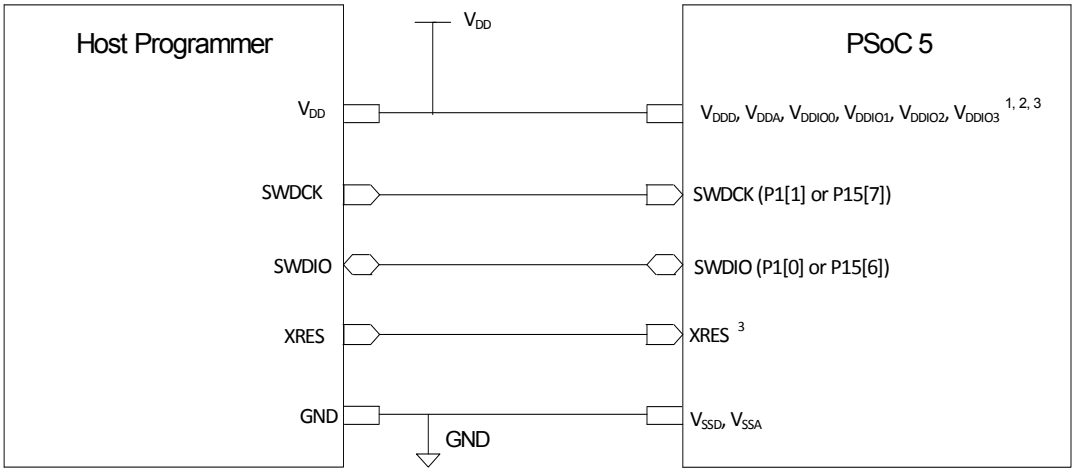
SWD uses two pins, either two of the JTAG pins (TMS and TCK) or the USBIO D+ and D- pins. The USBIO pins are useful for in system programming of USB solutions that would otherwise require a separate programming connector. One pin is used for the data clock and the other is used for data input and output.

SWD can be enabled on only one of the pin pairs at a time. This only happens if, within 8 µs (key window) after reset, that pin pair (JTAG or USB) receives a predetermined acquire sequence of 1s and 0s. If the NVL latches are set for SWD (see *Section 5.5*), this sequence need not be applied to the JTAG pin pair. The acquire sequence must always be applied to the USB pin pair.

SWD is used for debugging or for programming the flash memory.

The SWD interface can be enabled from the JTAG interface or disabled, allowing its pins to be used as GPIO. Unlike JTAG, the SWD interface can always be reacquired on any device during the key window. It can then be used to reenable the JTAG interface, if desired. When using SWD or JTAG pins as standard GPIO, make sure that the GPIO functionality and PCB circuits do not interfere with SWD or JTAG use.

Figure 9-2. SWD Interface Connections between PSoC 5LP and Programmer



[1] The voltage levels of the Host Programmer and the PSoC 5 voltage domains involved in programming should be the same. The XRES pin is powered by V_{DDIO1}. The USB SWD pins are powered by V_{DDD}. So for Programming using the USB SWD pins with XRES pin, the V_{DDD}, V_{DDIO1} of PSoC 5 should be at the same voltage level as Host V_{DD}. Rest of PSoC 5 voltage domains (V_{DDA}, V_{DDIO0}, V_{DDIO2}, V_{DDIO3}) need not be at the same voltage level as host Programmer. The Port 1 SWD pins are powered by V_{DDIO1}. So V_{DDIO1} of PSoC 5 should be at same voltage level as host V_{DD} for Port 1 SWD programming. Rest of PSoC 5 voltage domains (V_{DDD}, V_{DDA}, V_{DDIO0}, V_{DDIO2}, V_{DDIO3}) need not be at the same voltage level as host Programmer.

[2] Vdda must be greater than or equal to all other power supplies (Vddd, Vddio's) in PSoC 5.

[3] For Power cycle mode Programming, XRES pin is not required. But the Host programmer must have the capability to toggle power (Vddd, Vdda, All Vddio's) to PSoC 5. This may typically require external interface circuitry to toggle power which will depend on the programming setup. The power supplies can be brought up in any sequence, however, once stable, VDDA must be greater than or equal to all other supplies.

9.3 Debug Features

The CY8C56LP supports the following debug features:

- Halt and single-step the CPU
- View and change CPU and peripheral registers, and RAM addresses
- Six program address breakpoints and two literal access breakpoints
- Data watchpoint events to CPU
- Patch and remap instruction from flash to SRAM
- Debugging at the full speed of the CPU
- Compatible with PSoC Creator and MiniProg3 programmer and debugger
- Standard JTAG programming and debugging interfaces make CY8C56LP compatible with other popular third-party tools (for example, ARM / Keil)

9.4 Trace Features

The following trace features are supported:

- Instruction trace
- Data watchpoint on access to data address, address range, or data value
- Trace trigger on data watchpoint
- Debug exception trigger
- Code profiling
- Counters for measuring clock cycles, folded instructions, load/store operations, sleep cycles, cycles per instruction, interrupt overhead
- Interrupt events trace
- Software event monitoring, “printf-style” debugging

9.5 SWV and TRACEPORT Interfaces

The SWV and TRACEPORT interfaces provide trace data to a debug host via the Cypress MiniProg3 or an external trace port analyzer. The 5 pin TRACEPORT is used for rapid transmission of large trace streams. The single pin SWV mode is used to minimize the number of trace pins. SWV is shared with a JTAG pin. If debugging and tracing are done at the same time then SWD may be used with either SWV or TRACEPORT, or JTAG may be used with TRACEPORT, as shown in Table 9-1.

Table 9-1. Debug Configurations

Debug and Trace Configuration	GPIO Pins Used
All debug and trace disabled	0
JTAG	4 or 5
SWD	2
SWV	1
TRACEPORT	5
JTAG + TRACEPORT	9 or 10
SWD + SWV	3
SWD + TRACEPORT	7

9.6 Programming Features

The JTAG and SWD interfaces provide full programming support. The entire device can be erased, programmed, and verified. Designers can increase flash protection levels to protect firmware IP. Flash protection can only be reset after a full device erase. Individual flash blocks can be erased, programmed, and verified, if block security settings permit.

9.7 Device Security

PSoC 5LP offers an advanced security feature called device security, which permanently disables all test, programming, and debug ports, protecting your application from external access. The device security is activated by programming a 32-bit key (0x50536F43) to a Write Once Latch (WOL).

The Write Once Latch is a type of nonvolatile latch (NVL). The cell itself is an NVL with additional logic wrapped around it. Each WOL device contains four bytes (32 bits) of data. The wrapper outputs a ‘1’ if a super-majority (28 of 32) of its bits match a pre-determined pattern (0x50536F43); it outputs a ‘0’ if this majority is not reached. When the output is 1, the Write Once NV latch locks the part out of Debug and Test modes; it also permanently gates off the ability to erase or alter the contents of the latch. Matching all bits is intentionally not required, so that single (or few) bit failures do not deassert the WOL output. The state of the NVL bits after wafer processing is truly random with no tendency toward 1 or 0.

The WOL only locks the part after the correct 32-bit key (0x50536F43) is loaded into the NVL's volatile memory, programmed into the NVL's nonvolatile cells, and the part is reset. The output of the WOL is only sampled on reset and used to disable the access. This precaution prevents anyone from reading, erasing, or altering the contents of the internal memory.

The user can write the key into the WOL to lock out external access only if no flash protection is set (see “Flash Security” section on page 19). However, after setting the values in the WOL, a user still has access to the part until it is reset. Therefore, a user can write the key into the WOL, program the flash protection data, and then reset the part to lock it.

Table 11-2. DC Specifications (continued)

Parameter	Description	Conditions		Min	Typ	Max	Units
I_{DD}[22]	**Sleep Mode**[23]						
	CPU = OFF RTC = ON (= ECO32K ON, in low-power mode) Sleep timer = ON (= ILO ON at 1 kHz)[24] WDT = OFF I^2C Wake = OFF Comparator = OFF POR = ON Boost = OFF SIO pins in single ended input, unregulated output mode	$V_{DD} = V_{DDIO}$ = 4.5–5.5 V	T = –40 °C	–	1.9	3.1	µA
			T = 25 °C	–	2.4	3.6	
			T = 85 °C	–	5	16	
			T = 105 °C	–	5	16	
		$V_{DD} = V_{DDIO}$ = 2.7–3.6 V	T = –40 °C	–	1.7	3.1	
			T = 25 °C	–	2	3.6	
			T = 85 °C	–	4.2	16	
			T = 105 °C	–	4.2	16	
		$V_{DD} = V_{DDIO}$ = 1.71–1.95 V	T = –40 °C	–	1.6	3.1	
			T = 25 °C	–	1.9	3.6	
			T = 85 °C	–	4.2	16	
			T = 105 °C	–	4.2	16	
	Comparator = ON CPU = OFF RTC = OFF Sleep timer = OFF WDT = OFF I2C Wake = OFF POR = ON Boost = OFF SIO pins in single ended input, unregulated output mode	$V_{DD} = V_{DDIO}$ = 2.7–3.6 V[25]	T = 25 °C	–	3	4.2	µA
	I2C Wake = ON CPU = OFF RTC = OFF Sleep timer = OFF WDT = OFF Comparator = OFF POR = ON Boost = OFF SIO pins in single ended input, unregulated output mode	$V_{DD} = V_{DDIO}$ = 2.7–3.6 V[25]	T = 25 °C	–	1.7	3.6	µA

Notes
22. The current consumption of additional peripherals that are implemented only in programmed logic blocks can be found in their respective datasheets, available in PSoC Creator, the integrated design environment. To estimate total current, find CPU current at frequency of interest and add peripheral currents for your particular system from the device datasheet and component datasheets.
23. If V_{CCD} and V_{CCA} are externally regulated, the voltage difference between V_{CCD} and V_{CCA} must be less than 50 mV.
24. Sleep timer generates periodic interrupts to wake up the CPU. This specification applies only to those times that the CPU is off.
25. Based on device characterization (Not production tested).

Figure 11-1. Active Mode Current vs F_{CPU}, V_{DD} = 3.3 V, Temperature = 25 °C

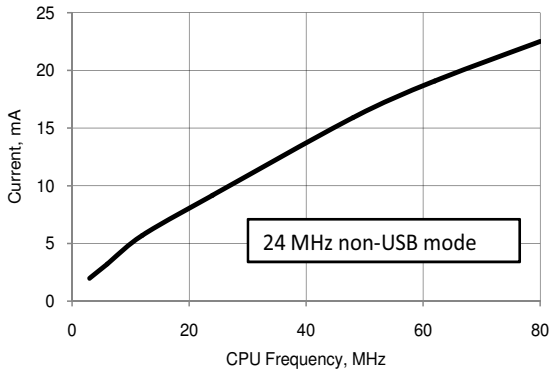


Figure 11-2. I_{DD} vs Frequency at 25 °C

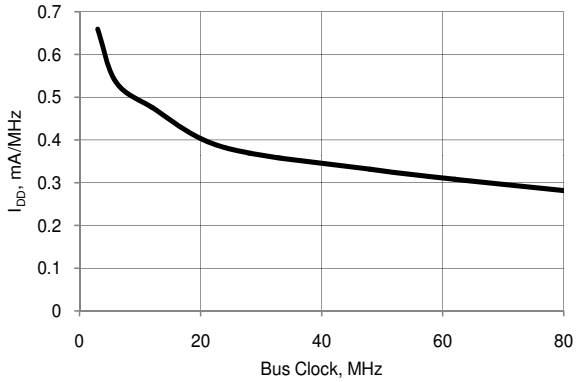


Figure 11-3. Active Mode Current vs Temperature and F_{CPU}, V_{DD} = 3.3 V

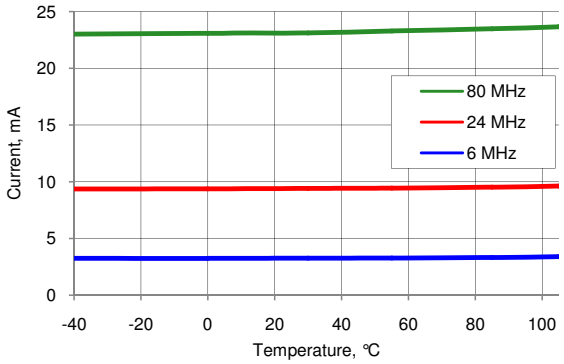


Figure 11-4. Active Mode Current vs V_{DD} and Temperature, F_{CPU} = 24 MHz

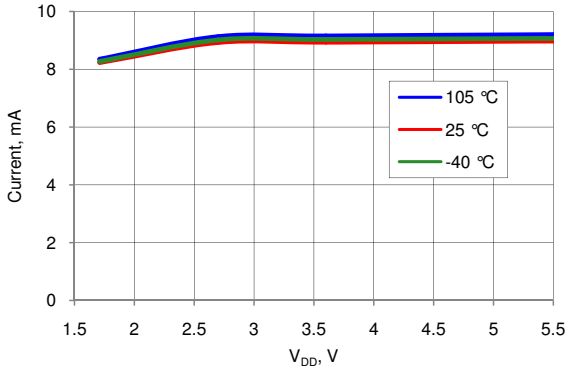


Table 11-3. AC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
F_{CPU}	CPU frequency	1.71 V ≤ V_{DDD} ≤ 5.5 V	DC	–	80.01	MHz
F_{BUSCLK}	Bus frequency	1.71 V ≤ V_{DDD} ≤ 5.5 V	DC	–	80.01	MHz
S_{VDD}[28]	V_{DD} ramp rate		–	–	0.066	V/µs
T_{IO_INIT}[28]	Time from V_{DDD}/V_{DDA}/V_{CCD}/V_{CCA} ≥ IPOR to I/O ports set to their reset states		–	–	10	µs
$T_{STARTUP}$[28]	Time from V_{DDD}/V_{DDA}/V_{CCD}/V_{CCA} ≥ PRES to CPU executing code at reset vector	V_{CCA}/V_{DDA} = regulated from V_{DDA}/V_{DDD}, no PLL used, fast IMO boot mode (48 MHz typ.)	–	–	33	µs
		V_{CCA}/V_{CCD} = regulated from V_{DDA}/V_{DDD}, no PLL used, slow IMO boot mode (12 MHz typ.)	–	–	66	µs
T_{SLEEP}[28]	Wakeup from sleep mode – Application of non-LVD interrupt to beginning of execution of next CPU instruction		–	–	25	µs
$T_{HIBERNATE}$[28]	Wakeup form hibernate mode – Application of external interrupt to beginning of execution of next CPU instruction		–	–	150	µs

Note
28. Based on device characterization (not production tested).

Figure 11-36. SAR ADC DNL vs Output Code, Bypassed Internal Reference Mode

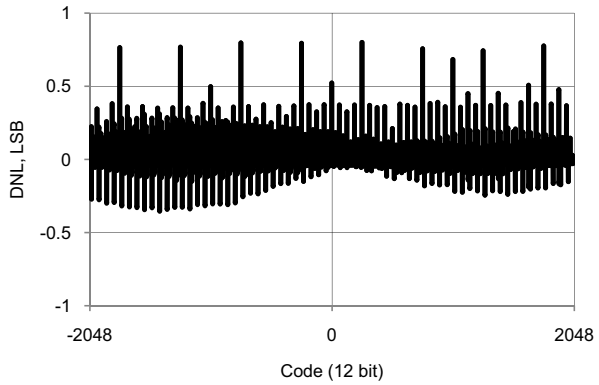


Figure 11-37. SAR ADC INL vs Output Code, Bypassed Internal Reference Mode

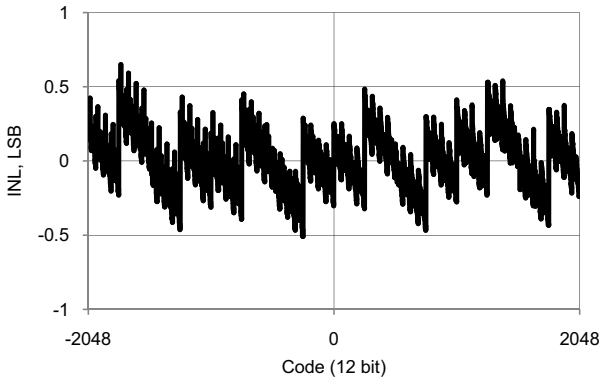


Figure 11-38. SAR ADC I_{DD} vs sps, V_{DDA} = 5 V, Continuous Sample Mode, External Reference Mode

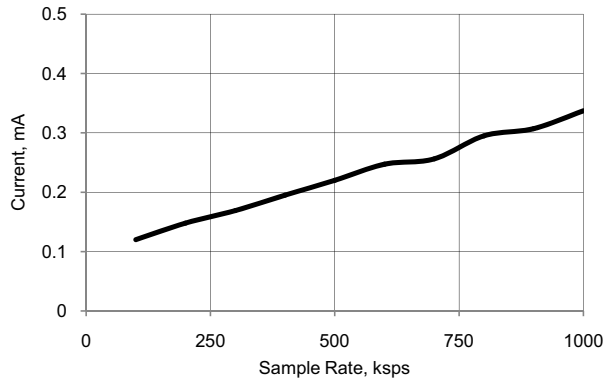


Table 11-25. SAR ADC AC Specifications[49]

Parameter	Description	Conditions	Min	Typ	Max	Units
A_SAMP_1	Sample rate with external reference bypass cap		–	–	1	Msps
A_SAMP_2	Sample rate with no bypass cap. Reference = V_{DD}		–	–	500	Ksps
A_SAMP_3	Sample rate with no bypass cap. Internal reference		–	–	100	Ksps
	Startup time		–	–	10	µs
SINAD	Signal-to-noise ratio		68	–	–	dB
THD	Total harmonic distortion		–	–	0.02	%

Figure 11-39. SAR ADC Noise Histogram, 100 ksps, Internal Reference No Bypass

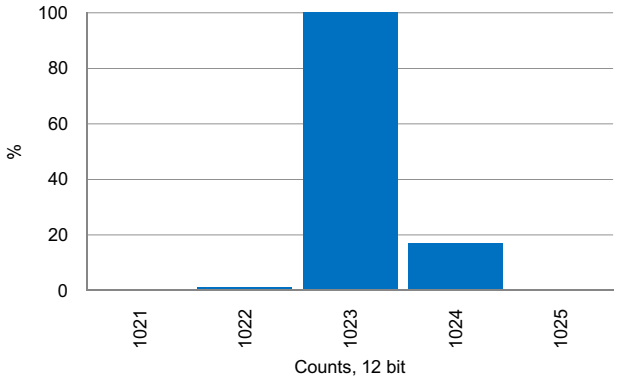


Figure 11-40. SAR ADC Noise Histogram, 1 msps, Internal Reference Bypassed

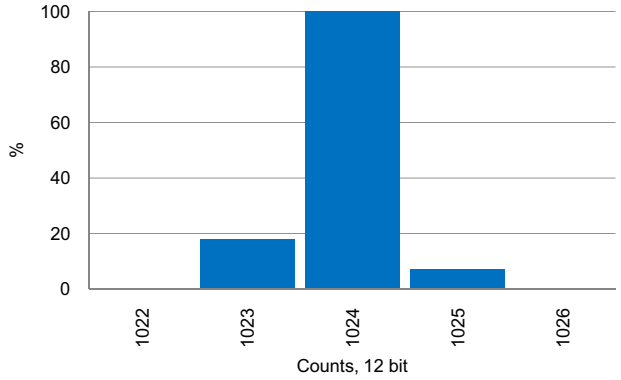
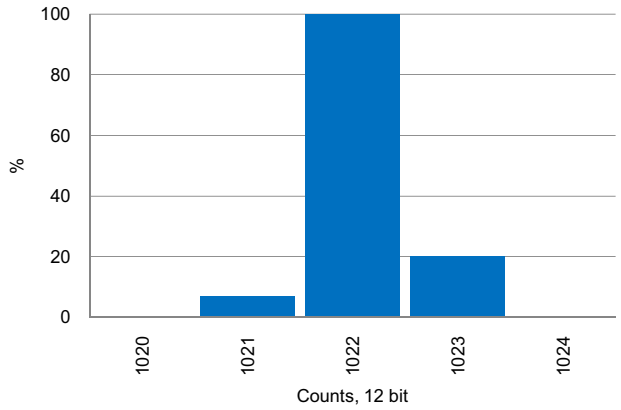


Figure 11-41. SAR ADC Noise Histogram, 1 msps, External Reference



Note
49. Based on device characterization (Not production tested).

Figure 11-48. IDAC Full Scale Error vs Temperature, Range = 255 µA, Source Mode

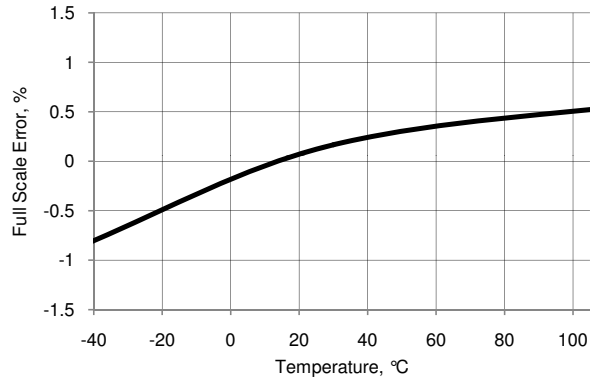


Figure 11-49. IDAC Full Scale Error vs Temperature, Range = 255 µA, Sink Mode

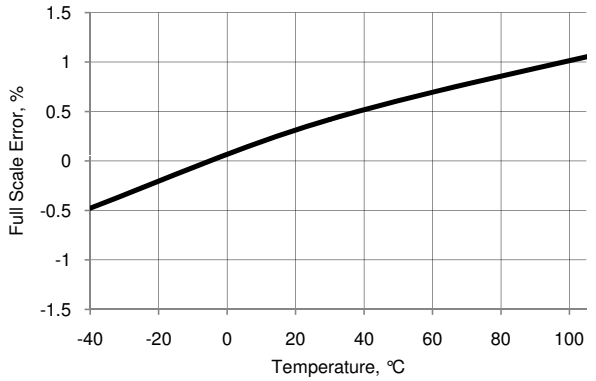


Figure 11-50. IDAC Operating Current vs Temperature, Range = 255 µA, Code = 0, Source Mode

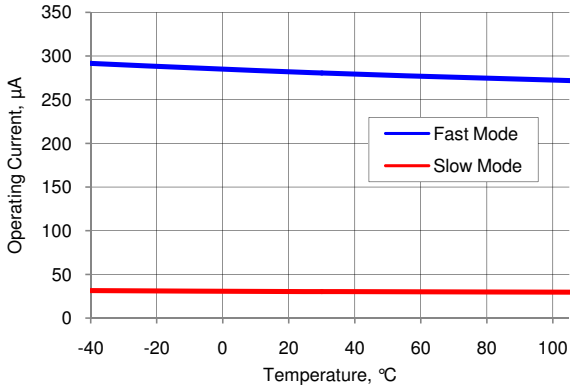


Figure 11-51. IDAC Operating Current vs Temperature, Range = 255 µA, Code = 0, Sink Mode

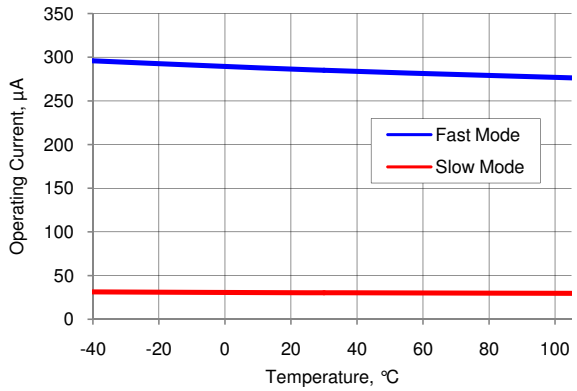


Table 11-31. IDAC AC Specifications[56]

Parameter	Description	Conditions	Min	Typ	Max	Units
F_{DAC}	Update rate		–	–	8	Msps
T_{SETTLE}	Settling time to 0.5 LSB	Range = 31.875 µA, full scale transition, fast mode, 600 Ω 15-pF load	–	–	125	ns
		Range = 255 µA, full scale transition, fast mode, 600 Ω 15-pF load	–	–	125	ns
	Current noise	Range = 255 µA, source mode, fast mode, Vdda = 5 V, 10 kHz	–	340	–	pA/sqrtHz

Note
56. Based on device characterization (Not production tested).

Table 11-39. PGA AC Specifications[62]

Parameter	Description	Conditions	Min	Typ	Max	Units
BW1	–3 dB bandwidth	Power mode = high, gain = 1, input = 100 mV peak-to-peak	6.7	8	–	MHz
		$T_A \le 105$ °C	6	8	–	
SR1	Slew rate	Power mode = high, gain = 1, 20% to 80%	3	–	–	V/µs
e_n	Input noise density	Power mode = high, V_{DDA} = 5 V, at 100 kHz	–	43	–	nV/sqrtHz

Figure 11-69. Bandwidth vs. Temperature, at Different Gain Settings, Power Mode = High

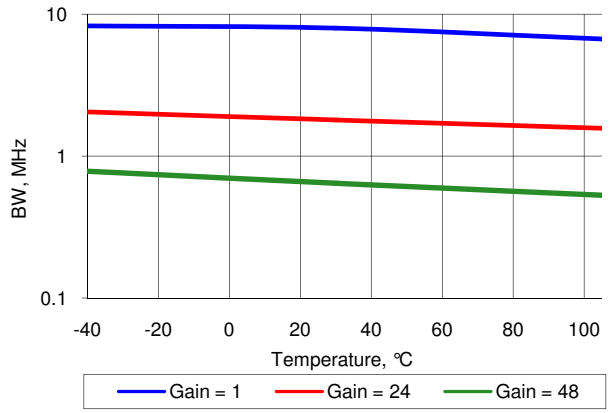
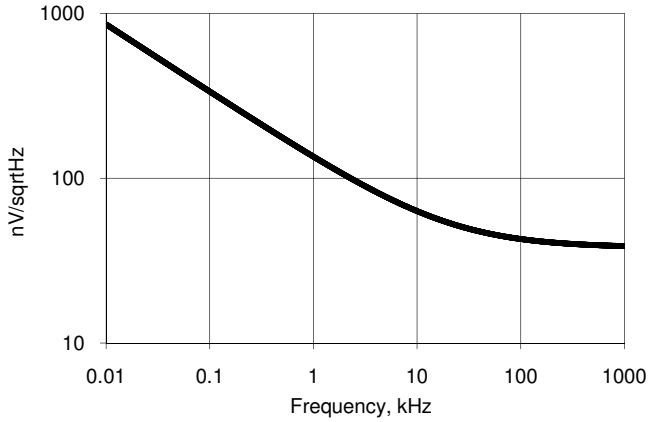


Figure 11-70. Noise vs. Frequency, Vdda = 5 V, Power Mode = High



11.5.12 Temperature Sensor

Table 11-40. Temperature Sensor Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
	Temp sensor accuracy	Range: –40 °C to +105 °C	–	±5	–	°C

11.5.13 LCD Direct Drive

Table 11-41. LCD Direct Drive DC Specifications[62]

Parameter	Description	Conditions	Min	Typ	Max	Units
I_{CC}	LCD Block (no glass)	Device sleep mode with wakeup at 400 Hz rate to refresh LCD, bus, clock = 3MHz, Vddio = Vdda = 3 V, 8 commons, 16 segments, 1/5 duty cycle, 40 Hz frame rate, no glass connected	–	81	–	µA
I_{CC_SEG}	Current per segment driver	Strong drive mode	–	260	–	µA
V_{BIAS}	LCD bias range (V_{BIAS} refers to the main output voltage(V0) of LCD DAC)	$V_{DDA} \ge 3$ V and $V_{DDA} \ge V_{BIAS}$	2	–	5	V
	LCD bias step size	$V_{DDA} \ge 3$ V and $V_{DDA} \ge V_{BIAS}$	–	9.1 × V_{DDA}	–	mV
	LCD capacitance per segment/ common driver	Drivers may be combined	–	500	5000	pF
	Maximum segment DC offset	$V_{DDA} \ge 3$V and $V_{DDA} \ge V_{BIAS}$	–	–	20	mV
I_{OUT}	Output drive current per segment driver)	V_{DDIO} = 5.5 V, strong drive mode	355	–	710	µA

Note
62. Based on device characterization (Not production tested).

11.7 Memory

Specifications are valid for –40 °C ≤ T_A ≤ 105 °C and T_J ≤ 120 °C, except where noted. Specifications are valid for 1.71 V to 5.5 V, except where noted.

11.7.1 Flash

Table 11-57. Flash DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
	Erase and program voltage	V_{DDD} pin	1.71	–	5.5	V

Table 11-58. Flash AC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
T_{WRITE}	Row write time (erase + program)		–	15	20	ms
T_{ERASE}	Row erase time		–	10	13	ms
	Row program time		–	5	7	ms
T_{BULK}	Bulk erase time (256 KB)		–	–	140	ms
	Sector erase time (16 KB)		–	–	15	ms
T_{PROG}	Total device programming time	No overhead[71]	–	5	7.5	seconds
	Flash data retention time, retention period measured from last erase cycle	Average ambient temp. T_A ≤ 55 °C, 100 K erase/program cycles	20	–	–	years
		Average ambient temp. T_A ≤ 85 °C, 10 K erase/program cycles	10	–	–	
		Ambient temp. T_A ≤ 105 °C, 10 K erase/program cycles, ≤ one year at T_A ≥ 75 °C [72]	10	–	–	

11.7.2 EEPROM

Table 11-59. EEPROM DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
	Erase and program voltage		1.71	–	5.5	V

Table 11-60. EEPROM AC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
T_{WRITE}	Single row erase/write cycle time		–	10	20	ms
	EEPROM data retention time, retention period measured from last erase cycle	Average ambient temp, T_A ≤ 25 °C, 1M erase/program cycles	20	–	–	years
		Average ambient temp, T_A ≤ 55 °C, 100 K erase/program cycles	20	–	–	
		Average ambient temp. T_A ≤ 85 °C, 10 K erase/program cycles	10	–	–	
		Ambient temp. T_A ≤ 105 °C, 10K erase/program cycles, ≤ one year at T_A ≥75 °C [72]	10	–	–	

Notes
71. See PSoC 5 Device Programming Specifications for a description of a low-overhead method of programming PSoC 5 flash.
72. Cypress provides a retention calculator to calculate the retention lifetime based on customers' individual temperature profiles for operation over the –40 °C to +105 °C ambient temperature range. Contact customercare@cypress.com.

11.8 PSoC System Resources

Specifications are valid for –40 °C ≤ T_A ≤ 105 °C and T_J ≤ 120 °C, except where noted. Specifications are valid for 1.71 V to 5.5 V, except where noted.

11.8.1 POR with Brown Out

For brown out detect in regulated mode, V_{DDD} and V_{DDA} must be ≥ 2.0 V. Brown out detect is not available in externally regulated mode.

Table 11-67. Precise Low-Voltage Reset (PRES) with Brown Out DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
PRESR	Rising trip voltage	Factory trim	1.64	–	1.68	V
PRESF	Falling trip voltage		1.62	–	1.66	V

Table 11-68. Power On Reset (POR) with Brown Out AC Specifications[78]

Parameter	Description	Conditions	Min	Typ	Max	Units
PRES_TR[79]	Response time		–	–	0.5	µs
	V_{DDD}/V_{DDA} droop rate	Sleep mode	–	5	–	V/sec

11.8.2 Voltage Monitors

Table 11-69. Voltage Monitors DC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
LVI	Trip voltage					
	LVI_A/D_SEL[3:0] = 0000b		1.68	1.73	1.77	V
	LVI_A/D_SEL[3:0] = 0001b		1.89	1.95	2.01	V
	LVI_A/D_SEL[3:0] = 0010b		2.14	2.20	2.27	V
	LVI_A/D_SEL[3:0] = 0011b		2.38	2.45	2.53	V
	LVI_A/D_SEL[3:0] = 0100b		2.62	2.71	2.79	V
	LVI_A/D_SEL[3:0] = 0101b		2.87	2.95	3.04	V
	LVI_A/D_SEL[3:0] = 0110b		3.11	3.21	3.31	V
	LVI_A/D_SEL[3:0] = 0111b		3.35	3.46	3.56	V
	LVI_A/D_SEL[3:0] = 1000b		3.59	3.70	3.81	V
	LVI_A/D_SEL[3:0] = 1001b		3.84	3.95	4.07	V
	LVI_A/D_SEL[3:0] = 1010b		4.08	4.20	4.33	V
	LVI_A/D_SEL[3:0] = 1011b		4.32	4.45	4.59	V
	LVI_A/D_SEL[3:0] = 1100b		4.56	4.70	4.84	V
	LVI_A/D_SEL[3:0] = 1101b		4.83	4.98	5.13	V
	LVI_A/D_SEL[3:0] = 1110b		5.05	5.21	5.37	V
	LVI_A/D_SEL[3:0] = 1111b		5.30	5.47	5.63	V
HVI	Trip voltage		5.57	5.75	5.92	V

Table 11-70. Voltage Monitors AC Specifications

Parameter	Description	Conditions	Min	Typ	Max	Units
LVI_tr[79]	Response time		–	–	1	µs

Notes
78. Based on device characterization (Not production tested).
79. This value is calculated, not measured.